# **MOSFET** - Power, Single, **N-Channel** 40 V, 2.1 mΩ, 163 A

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage			$V_{DSS}$	40	٧
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain Cur-		T <sub>C</sub> = 25°C	I <sub>D</sub>	163	Α
rent $R_{\theta JC}$ (Notes 1 & 3)	Steady	T <sub>C</sub> = 100°C		115	
Power Dissipation R <sub>θJC</sub>	State	T <sub>C</sub> = 25°C	$P_{D}$	117	W
(Note 1)		T <sub>C</sub> = 100°C		58	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	26	Α
Current R <sub>0JA</sub> (Notes 1, 2 & 3)	Steady State	T <sub>A</sub> = 100°C		22	
Power Dissipation R <sub>θJA</sub>		T <sub>A</sub> = 25°C	$P_{D}$	3.2	W
(Notes 1 & 2)		T <sub>A</sub> = 100°C		2.2	
Pulsed Drain Current	T <sub>A</sub> = 25°	C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			I <sub>S</sub>	130	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, I <sub>L(pk)</sub> = 25 A)			E <sub>AS</sub>	420	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{\theta JC}$	1.28	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	48	

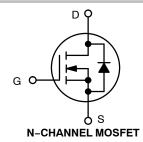
- 1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
   Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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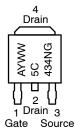
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	
40 V	2.1 m $\Omega$ @ 10 V	163 A	





**DPAK CASE 369C** STYLE 2

### MARKING DIAGRAM **& PIN ASSIGNMENT**



= Assembly Location

= Year WW = Work Week 5C434N= Device Code = Pb-Free Package

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•		
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				18		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μΑ
		$V_{GS} = 0 V$ , $V_{DS} = 40 V$	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	2.0		4.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.9		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS}$ = 10 V, $I_{D}$	= 50 A		1.7	2.1	mΩ
Forward Transconductance	9FS	$V_{DS} = 3 \text{ V}, I_{D}$	= 50 A		155		S
CHARGES, CAPACITANCES AND GATE RE	SISTANCES						
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = 25 \text{ V}$			5400		pF
Output Capacitance	C <sub>oss</sub>				3000		1
Reverse Transfer Capacitance	C <sub>rss</sub>				71		1
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 32 \text{ V},$ $I_{D} = 50 \text{ A}$			80.6		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				15.2		1
Gate-to-Source Charge	Q <sub>GS</sub>				25.2		1
Gate-to-Drain Charge	$Q_{GD}$				15.4		1
Plateau Voltage	$V_{GP}$				4.8		V
SWITCHING CHARACTERISTICS (Note 5)					•		
Turn-On Delay Time	t <sub>d(on)</sub>				15		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>D</sub>	e = 32 V.		78		1 !
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 32 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 2.5 \Omega$			43		
Fall Time	t <sub>f</sub>				14		
DRAIN-SOURCE DIODE CHARACTERISTIC	S					1	
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	V
		$I_S = 50 \text{ A}$	T <sub>J</sub> = 125°C		0.7		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS}$ = 0 V, dls/dt = 100 A/ $\mu$ s, $I_{S}$ = 50 A			73		ns
Charge Time	ta				36		1
Discharge Time	tb				37		1
Reverse Recovery Charge	Q <sub>RR</sub>				120		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.

5. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**

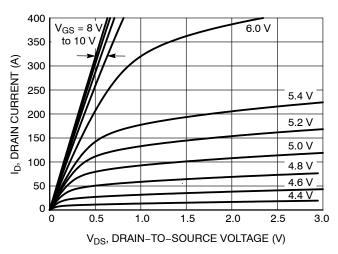


Figure 1. On-Region Characteristics

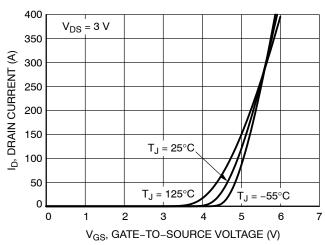


Figure 2. Transfer Characteristics

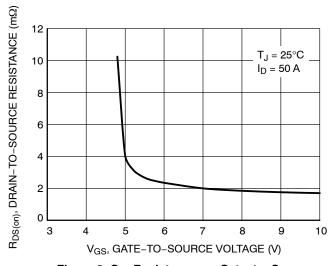


Figure 3. On-Resistance vs. Gate-to-Source Voltage

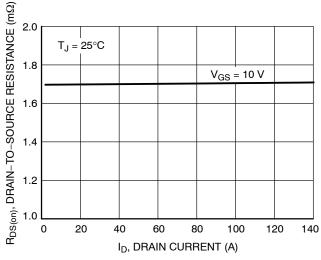


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

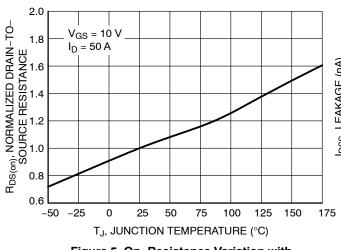


Figure 5. On–Resistance Variation with Temperature

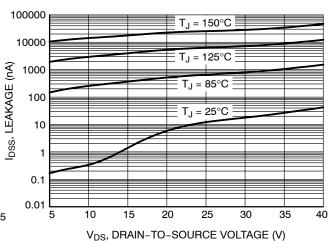


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

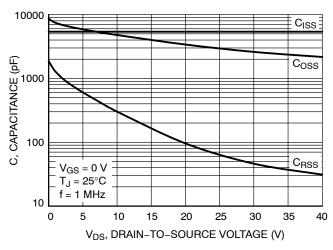


Figure 7. Capacitance Variation

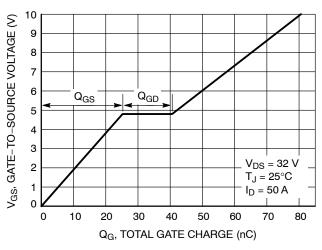


Figure 8. Gate-to-Source vs. Total Charge

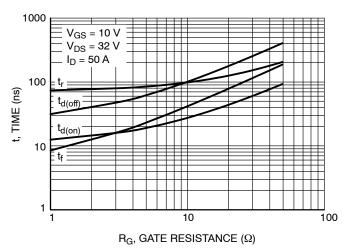


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

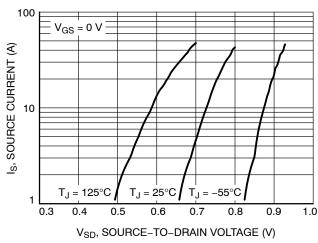


Figure 10. Diode Forward Voltage vs. Current

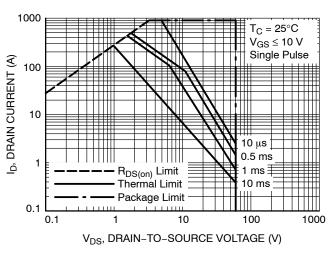


Figure 11. Maximum Rated Forward Biased Safe Operating Area

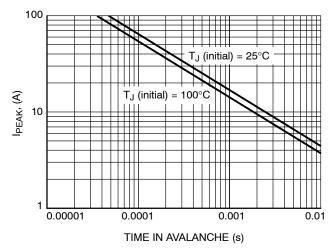


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

## **TYPICAL CHARACTERISTICS**

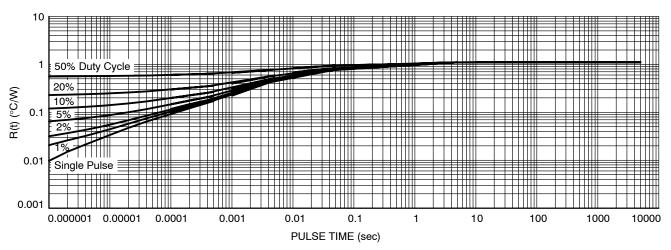


Figure 13. Thermal Characteristics

#### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NVD5C434NT4G	DPAK (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

**DETAIL A** ROTATED 90° CW

STYLE 2:

STYLE 1:

# **DPAK (SINGLE GAUGE)** CASE 369C **ISSUE F**

**DATE 21 JUL 2015** 

#### NOTES:

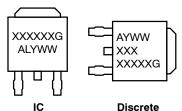
- IOTES: 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

- MENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
  5. DIMENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

  6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

	INCHES		MILLIM	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114	REF	2.90 REF		
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

## **GENERIC MARKING DIAGRAM\***



XXXXXX = Device Code

= Assembly Location Α

L = Wafer Lot Υ = Year

WW = Work Week G = Pb-Free Package

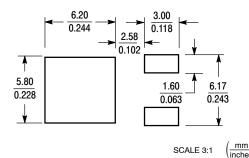
\*This information is generic. Please refer to device data sheet for actual part marking.

# SCALE 1:1 - h3 В L3 € DETAIL A NOTE 7 **BOTTOM VIEW** Ce SIDE VIEW | $\oplus$ | 0.005 (0.13) lacktriangledown C **TOP VIEW** Z Ħ L2 GAUGE C SEATING **BOTTOM VIEW** Δ1 ALTERNATE CONSTRUCTIONS

PIN 1. BASE 2. COLLE 3. EMITTE 4. COLLE	ER 3. SOL	JIN 2. CA	THODE :	1. CATHODE 2. ANODE 3. GATE 4. ANODE	PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE
STYLE 6: PIN 1. MT1 2. MT2 3. GATE 4. MT2	STYLE 7: PIN 1. GATE 2. COLLECTOR 3. EMITTER 4. COLLECTOR	3. ANODE	3. RESIS	IODE STOR ADJUST	STYLE 10: PIN 1. CATHODE 2. ANODE 3. CATHODE 4. ANODE

STYLE 3:

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolled except when accessed directly from the Document Reposit Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK (SINGLE GAUGE)		PAGE 1 OF 1	

STYLE 5:

STYLE 4:

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